				Specifications					
No.	lte	em	Temperature Compensating Type	High Dielectric Type	Test Method				
1	Operating Temperat Range	•	5C : -55 to +125°C	R7 : −55 to +125°C R6 : −30 to +85°C					
2	Rated Voltage		See the previous pag	ges	The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V <sup>P.P</sup> or V <sup>O.P</sup> , whichever is larger, should be maintained within the rated voltage range.				
3	Appearar	nce	No defects or abnorr	nalities	Visual inspection				
4	Dimensio	ons	Within the specified	dimensions	Using calipers				
5	Dielectric Strength		No defects or abnorr	nalities	No failure should be observed when 300% of the rated voltage (5C) or 250% of the rated voltage (R7) is applied between the terminations for 1 to 5 seconds, provided the charge/discharge current is less than 50mA.				
6	Insulation Resistance		More than 10,000M (Whichever is smalle		The insulation resistance should be measured with a DC voltage not exceeding the rated voltage at 25°C and 75%RH max. and within 2 minutes of charging.				
7	Capacita	nce	Within the specified	tolerance	The capacitance/Q/D.F. should be measured at 25°C at the				
8	Q/ Dissipatio (D.F.)	on Factor	30pF min. : Q≥1000 30pF max. : Q≥400+20C C : Nominal	Char.         25V min.         16V         10V         6.3V           R7, R6         0.025         0.035         0.035         0.05           max.         max.         max.         max.	frequency and voltage shown in the table.				
			Capacitance (pF)		Voltage 0.5 to 5Vrms 1.0±0.2Vrms				
		Capacitance Change Temperature	Within the specified tolerance (Table A) Within the specified tolerance	$\begin{tabular}{ c c c c c c c c c c c c c c c c c c c$	The capacitance change should be measured after 5 min. at each specified temperature stage. (1) Temperature Compensating Type The temperature coefficient is determined using the capaci- tance measured in step 3 as a reference. When cycling the temperature sequentially from step1 through 5, the capacitance should be within the specified tolerance for the temperature coefficient and capacitance change as Table A. The capacitance drift is calculated by dividing the differences between the maximum and minimum measured values in the				
9	Capacitance Temperature Characteristics	Coefficent	(Table A)		steps 1, 3 and 5 by the cap. value in step 3.				
		Capacitance Drift		Step         Temperature (°C)           1         25±2           2         -55±3 (for 5C/R7), -30±3 (for F5)           3         25±2           4         125±3 (for 5C/R7), 85±3 (for F5)           5         20±2					
				(2) High Dielectric Constant Type The ranges of capacitance change compared with the above 25°C value over the temperature ranges shown in the table should be within the specified ranges.					
10		hesive Strength Termination		GNM 2	Solder the capacitor to the test jig (glass epoxy board) shown in Fig.1 using a eutectic solder. Then apply 5N force in parallel with the test jig for $10\pm1$ sec.The soldering should be done either with an iron or using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock.Type a b c d GNM1M2 0.5 1.6 0.32 0.32				
				Copper foil	GNM212         0.4         1.8         0.15         0.5           GNM214         0.6         2.0         0.25         0.25           GN□314         0.8         2.5         0.4         0.4           (in mm)				
					Fig. 1				

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			Specifications					- Test Method				
No.	Item		Temperature Compensating Type High Dielectric Type			Туре						
		Appearance	No defects or abnorn	nalities				Solder the capacitor to the test jig (glass epoxy board) in the				
11		Capacitance	Within the specified tolerance					same manner and under the same conditions as (10). The capacitor should be subjected to a simple harmonic motion				
	Vibration Resistance	Q/D.F.	30pF min. : Q≥1000 30pF max. : Q≥400+20C C : Nominal Capacitance (pF)	R/ R61	16V 0.035 max.	10V 0.035 max.	6.3V 0.05 max.	having a total amplitude of 1.5mm, the frequency being vari uniformly between the approximate limits of 10 and 55Hz. T frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 minute. This motion should applied for a period of 2 hours in each 3 mutually perpendic directions (total of 6 hours).				
			No cracking or marki	ng defects should c	occur			Solder the capacitor on the test jig (glass epoxy board) shown				
			•GNM□□4	•GNM		E) C	)	in Fig. 2 using a eutectic solder. Then apply a force in the direction shown in Fig. 3 for $5\pm1$ sec. The soldering should be done either with an iron or using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock.				
12	Deflectior	ı				.0	0	20 50 Pressurizing speed : 1.0mm/sec. Pressurize				
			$\begin{array}{c c c c c c c c c c c c c c c c c c c $				1 ±0.05 :0.05 :0.05 :0.05	Capacitance meter 45 45 Fig. 3				
				Fig. 2								
13	Solderability of Termination		75% of the terminations are to be soldered evenly and continuously.			ly and	Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion). Preheat at 80 to 120°C for 10 to 30 seconds. After preheating, immerse in eutectic solder solution for 2±0.5 seconds at 230±5°C.					
	Resistance to Soldering Heat		The measured and observed characteristics should satisfy the specifications in the following table.				sfy the					
		Appearance	No marking defects	2.5% *±0.25pF B7 B6 · Within +7 5%								
		Capacitance Change	Within ±2.5% or ±0.25pF (Whichever is larger)					Preheat the capacitor at 120 to $150^{\circ}$ C for 1 minute. Immerse the capacitor in a eutectic solder solution at $270\pm5^{\circ}$ C for $10\pm0.5$ seconds. Let sit at room temperature for $24\pm2$ hours (temperature compensating type) or $48\pm4$ hours (high dielection				
14			30pF min. : Q≧1000				constant type), then measure.					
		30pF max. : Q/D.F. Q≥400+2	Q≧400+20C	Char. 25V min. R7, R6	16V 0.035	10V 0.035	6.3V 0.05	<ul> <li>Initial measurement for high dielectric constant type Perform a heat treatment at 150+0/-10°C for one hour and</li> </ul>				
			C : Nominal Capacitance (pF)	K7, K0 max.	max.	max.	max.	then let sit for 48±4 hours at room temperature. Perform the initial measurement.				
		I.R.	More than 10,000M	2 or 500Ω • F (Whic	hever is	smaller)	)					
		Dielectric Strength	No failure									

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	la ltom		Specifications					Took Marker d							
No.	Ite	em	Temperature Compensating Type	High Dielectric Type				- Test Method							
15	Tempera Cycle		specifications in the	observed characteristics should satisfy the following table.				Fix the capacitor to the supporting jig in the same manner and under the same conditions as (10). Perform the five cycles							
		Appearance Capacitance Change	No marking defects Within ±2.5% or ±0.25pF (Whichever is Inggor)	R7, R6	: Within ±	±7.5%			according to the table. Let sit for or 48±4 hours	according to the four heat treatments listed in the following table. Let sit for $24\pm 2$ hours (temperature compensating type) or $48\pm 4$ hours (high dielectric constant type) at room temperature, then measure.					
		Q/D.F.	larger) 30pF min. : Q≥1000 30pF max. : Q≥400+20C C:Nominal	Char. R7, R6	25V min. 0.025 max.	16V 0.035 max.	10V 0.035 max.	6.3V 0.05 max.	Step         1         2         3           Temp. (°C)         Min. Operating Temp. +0/-3         Room Temp.         Max. Operating Temp. +3/-0           Time (min.)         30±3         2 to 3         30±3		Max. Operating Temp. +3/–0	4 Room Temp. 2 to 3			
			Capacitance (pF)							•		ic constant type 10°C for one h			
		I.R. Dielectric Strength	More than 10,000M	2 or 500Ω	∙ F (Whi	chever i	s smaller	.)	<ul> <li>Perform a heat treatment at 150+0/-10°C for one hour and then let sit for 48±4 hours at room temperature.</li> <li>Perform the initial measurement.</li> </ul>						
	Humidity State		The measured and c specifications in the			istics sh	ould sati	sfy the							
		Appearance	No marking defects						-						
		Capacitance Change	Within ±5% or ±0.5pF (Whichever is larger)	R7, R6	: Within <del>1</del>	±12.5%			Sit the capacitor at $40\pm2^{\circ}$ C and 90 to 95% humidity for 500±						
16		Q/D.F.	30pF and over : Q≧350 10pF and over, 30pF and below: Q≧275+5C/2 10pF and below : Q≧200+10C C : Nominal Capacitance (pF)	Char. R7, R6	25V mii 0.05 max.	n. 16\ 0.0 max	5 (	//6.3V ).05 nax.	hours. Remove and I	et sit for 24±2 hours (temperature compensating nours (high dielectric constant type) at room			npensating		
		I.R.	More than 1,000M $\Omega$	or 50Ω • I	F (Which	ever is s	maller)								
		Dielectric Strength	No failure												
	Humidity	Load	The measured and o specifications in the	bserved characteristics should satisfy the following table.				_							
		Appearance Capacitance Change	No marking defects Within ±7.5% or ±0.75pF (Whichever is larger)	R7, R6	: Within ±	±12.5%			Apply the rated voltage at 40±2°C and 90 to 95% humidity 500±12 hours.						
17		Q/D.F.	30pF and over : Q≥200 30pF and below : Q≧100+10C/3	Char. R7, R6	25V mir 0.05 max.	n. 16V 0.05 max	5 C	//6.3V 0.05 nax.	type) or 48±4 temprature, th	and let sit for 24±2 hours(temperature compens 48±4 hours (high dielectric constant type) at roo ure, then muasure. Irge/discharge current is less than 50mA.					
			C : Nominal Capacitance (pF)												
		I.R.	More than $500M\Omega$ of	25Ω • F	(Whichev	er is sm	aller)		-						
		Dielectric Strength	No failure												

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				Specifications	TestMalled		
No.	Item		Temperature Compensating Type	High Dielectric Type	Test Method		
	High Tem Load	perature	The measured and o specifications in the f	bserved characteristics should satisfy the ollowing table.			
		Appearance	No marking defects				
		Capacitance Change	Within ±3% or ±0.3pF (Whichever is larger)	R7, R6 : Within ±12.5%	Apply 200% of the rated voltage for $1000\pm12$ hours at the maximun operating temperature $\pm3$ °C. Let sit for $24\pm2$ hours(temperature compensating type) or $48\pm4$ hours(high dielectric constant type) at room temperature, then measure.		
18		Q/D.F.	30pF and over : Q≥350 10pF and over, 30pF and below : Q≥275+5C/2 10pF and below : Q≥200+10C C : Nominal Capacitance (pF)	Char.         25V min.         16V         10V/6.3V           R7, R6         0.04         0.05         0.05           max.         max.         max.         max.	<ul> <li>The charge/discharge current is less than 50mA.</li> <li>Initial measurement for high dielectric constant type.</li> <li>Apply 200% of the rated DC voltage for one hour at the maximun operating temperature ±3°C. Remove and let sit for 48±4 hours at room temperature.Perform initial measurement.</li> </ul>		
		I.R.	More than 1,000M $\Omega$	or $50\Omega \cdot F$ (Whichever is smaller)			

## Table A

		Capacitance Change from 25°C (%)						
Char.	Nominal Values (ppm/℃) Note 1	—55℃		-3	<b>℃</b>	−10°C		
		Max.	Min.	Max.	Min.	Max.	Min.	
5C	0±30	0.58	-0.24	0.40	-0.17	0.25	-0.11	

Note 1 : Nominal values denote the temperature coefficient within a range of 25 to 125°C.

